

# **An 8bit, 2.6ps Two-Step TDC in 65nm CMOS Employing a Switched Ring-Oscillator Based Time Amplifier**

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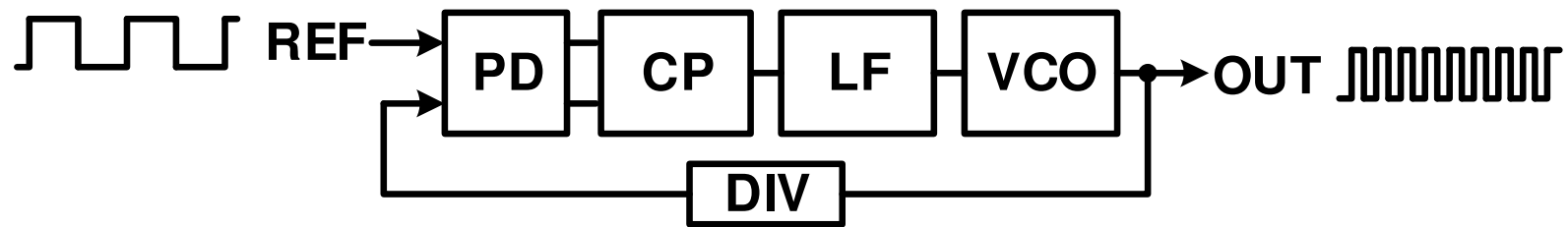
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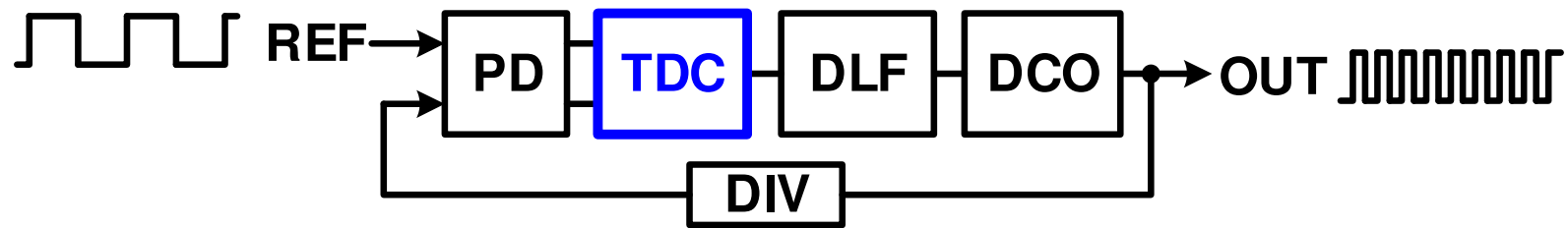
# Agenda

- **Conventional Time-to-Digital Converters**
- **Proposed Switched Ring Oscillator Based Time Amplifier Circuit**
- **TDC Test Chip Configuration**
- **Measurement Results**
- **Conclusion**

# Analog/Digital Phase Locked Loops



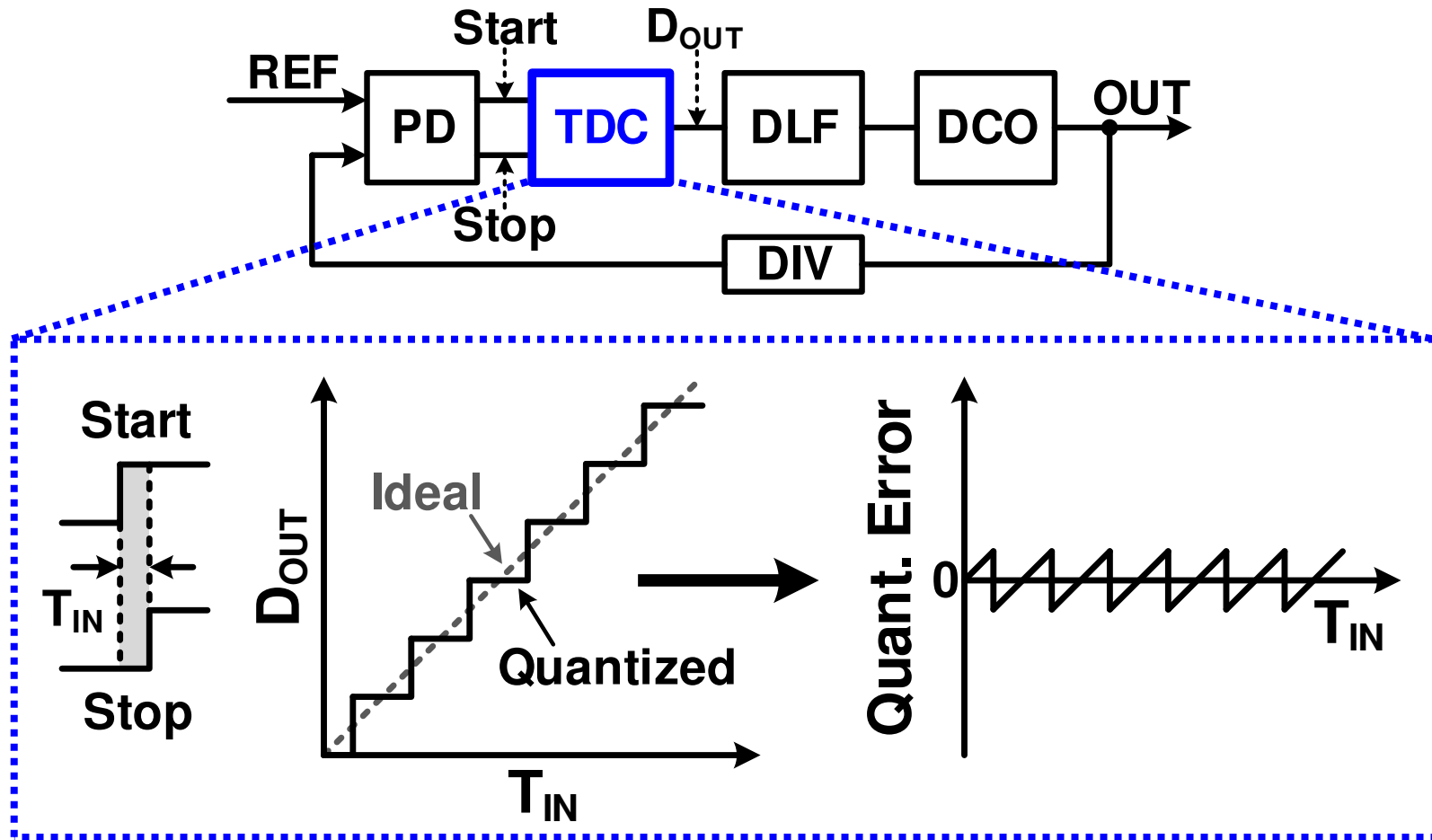
**Analog PLL**



**Digital PLL**

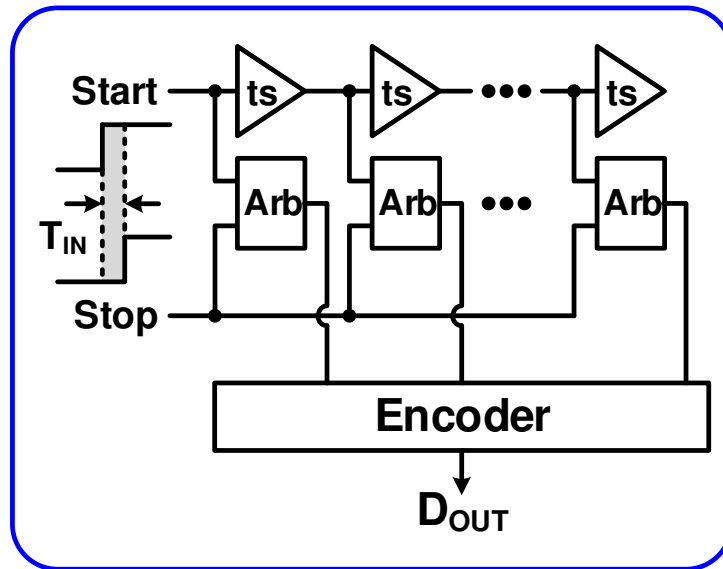
- Compact area, scalable, insensitive to supply noise, etc.
- Phase noise degradation due to quantization error

# TDC Quantization Noise

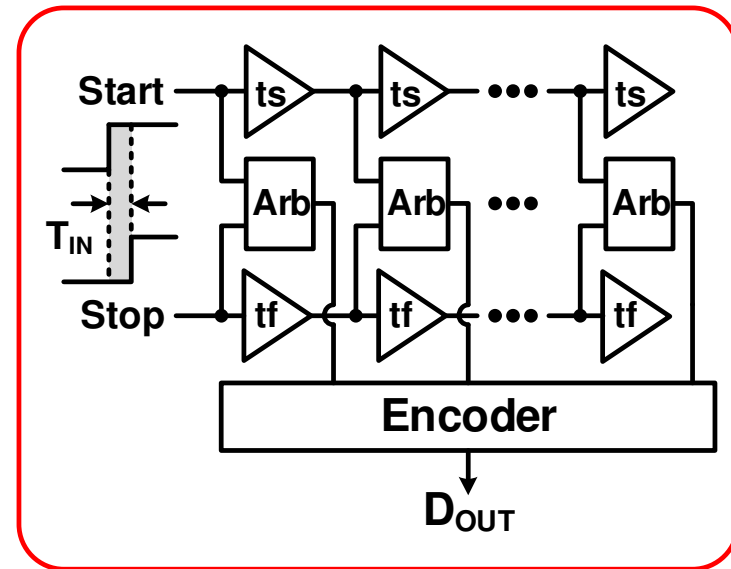


- Critical building blocks of DPLL: TDC and DCO
- TDC quantization error degrades PLL in-band phase noise

# Conventional TDCs and Trade-offs



**Delay Line (DL)**



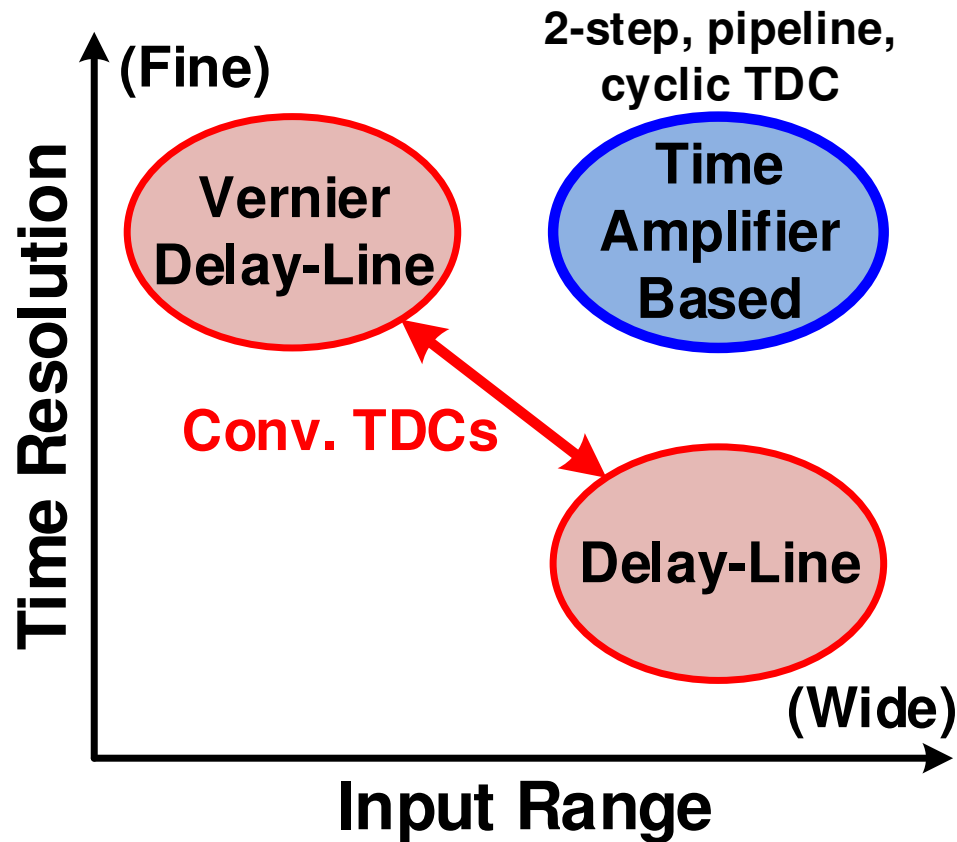
**Vernier Delay Line (VDL)**

	DL TDC		VDL TDC	
Resolution	ts	40ps	ts-tf	2ps
Input Range	$2^N \cdot ts$	10.24ns	$2^N \cdot (ts-tf)$	0.512ns
Conv. Time	$2^N \cdot ts$	10.24ns	$2^N \cdot ts$	10.24ns

\*e.g. 8bit TDC with two delay cells (i.e. ts=40ps and tf=38ps)

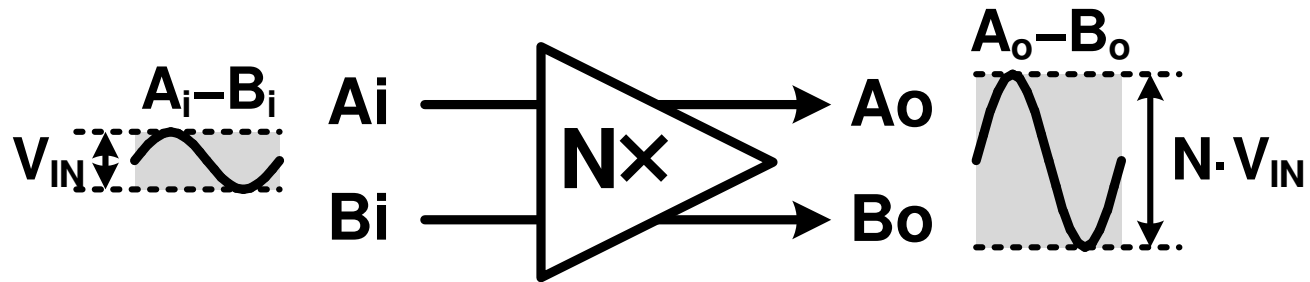
- Trade-off between time resolution and input range

# TDC Resolution vs. Input Range

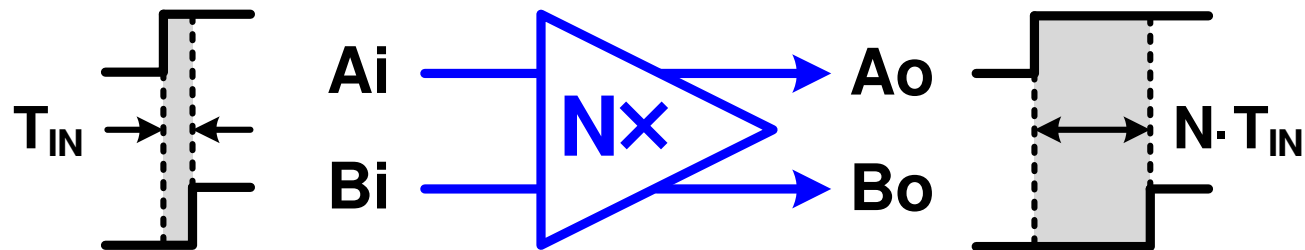


- To achieve both fine time resolution and wide input range
- Time amplifier (TA) based TDCs: two-step, pipeline, etc.

# Voltage vs. Time Amplifier



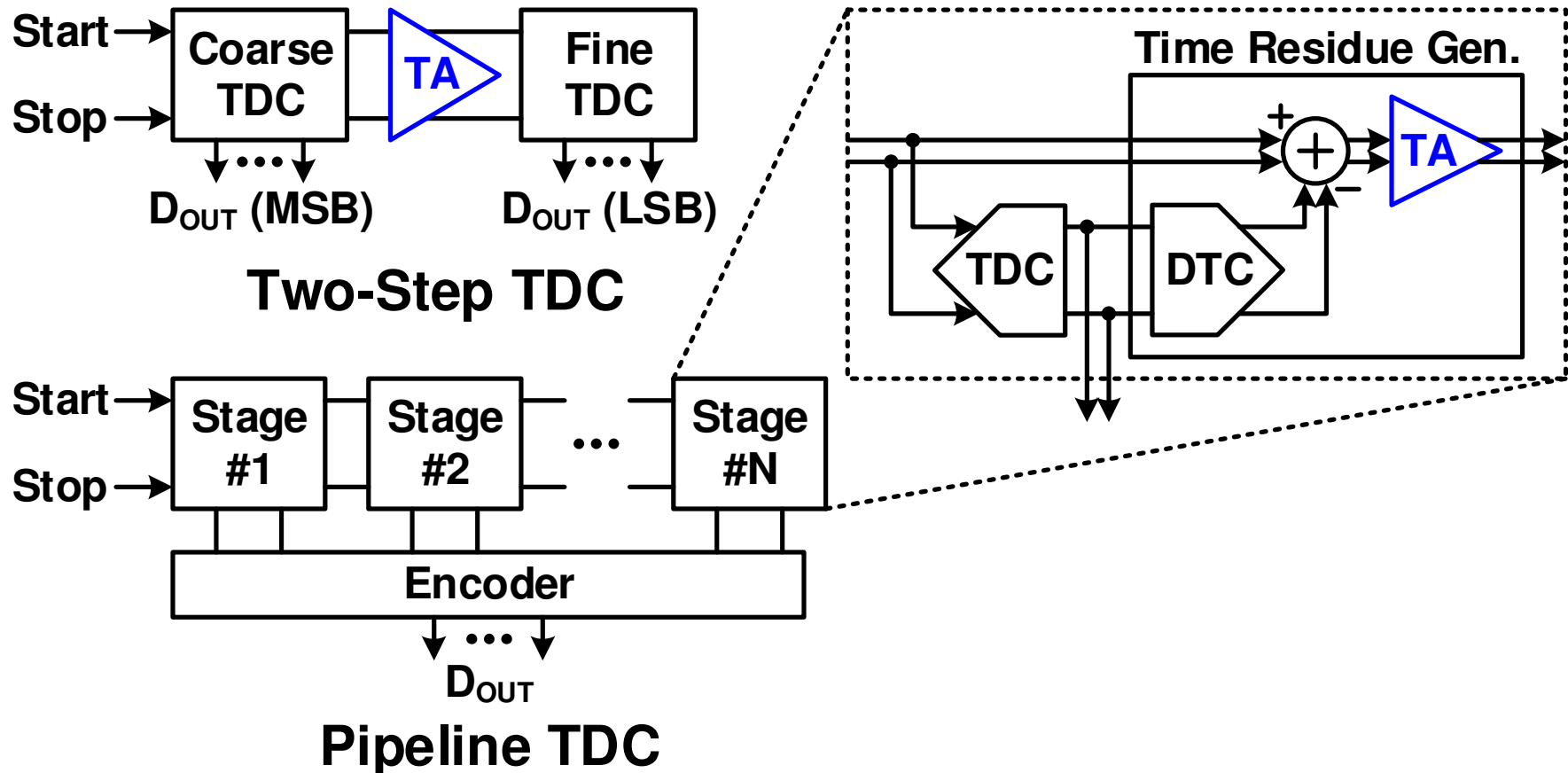
## Voltage Amplifier



## Time Amplifier (TA)

- Amplify time (input phase difference) instead of voltage

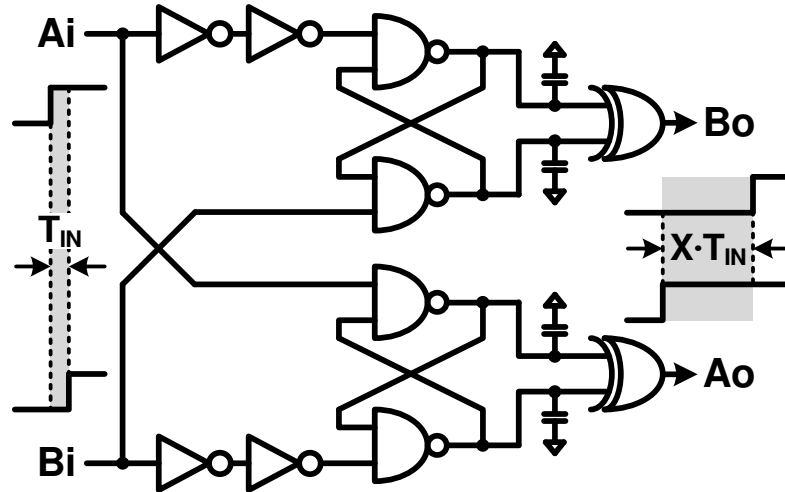
# Time Amplifier Based TDC Types



- **Two-step TDC: Coarse and Fine resolution TDC+TA**
- **Pipeline TDC: Cascaded stages of TDC+DTC+TA circuits**

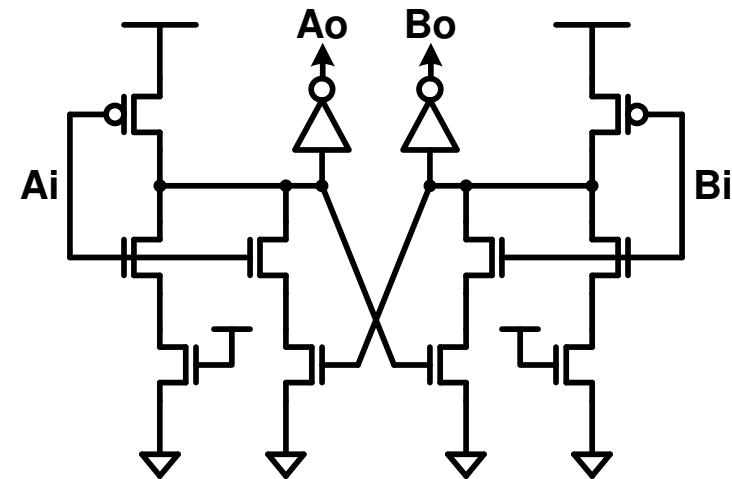


# Existing Time Amplifier Circuits



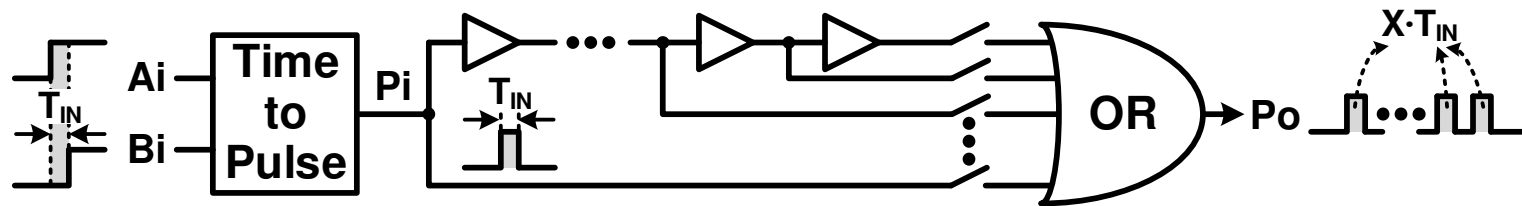
**SR latch metastability based**

- ✓ Unpredictable TA gain
- ✓ Narrow input range



**Discharging time control based**

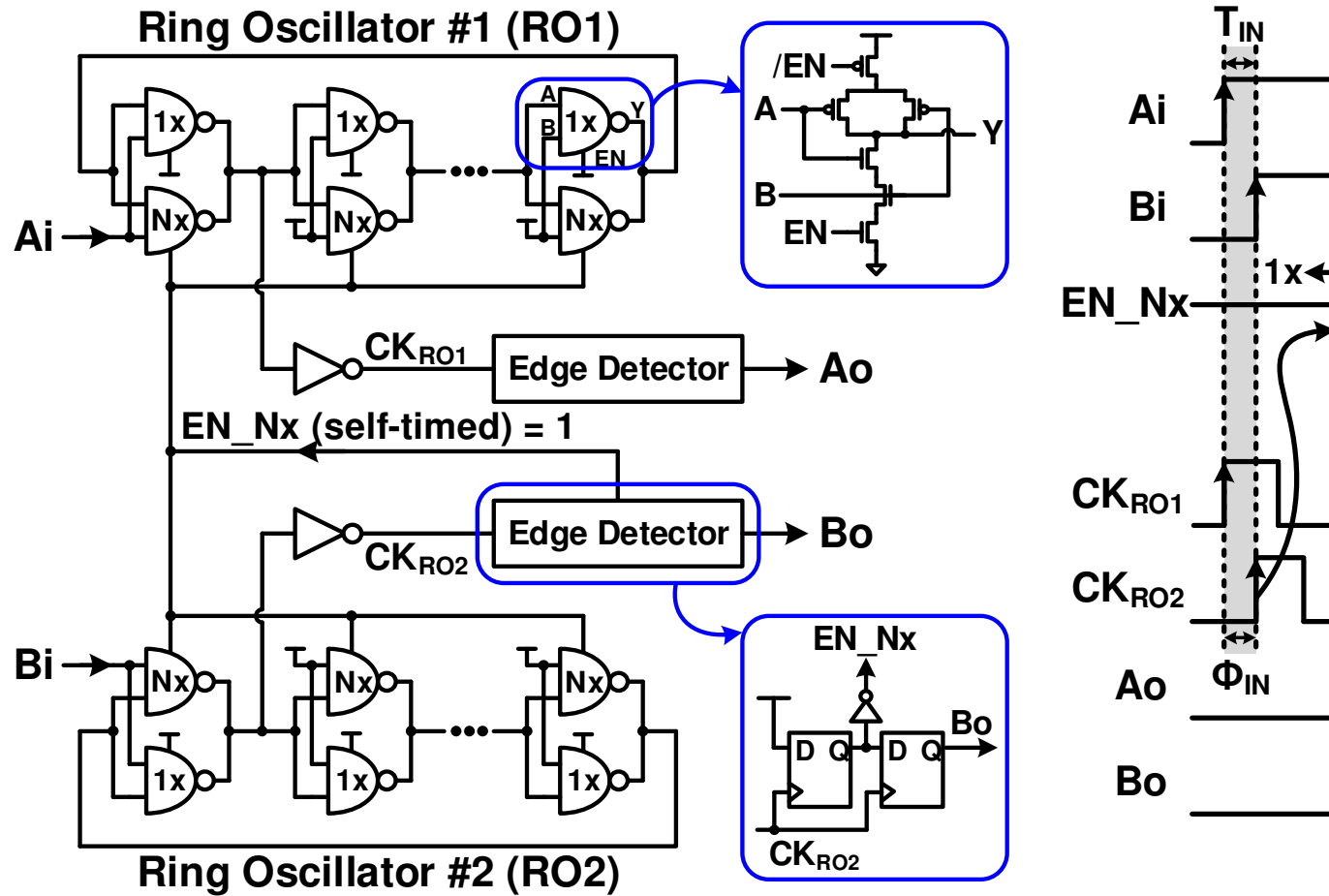
- ✓ Large TA gain error
- ✓ Requires background calibration



**Pulse train based**

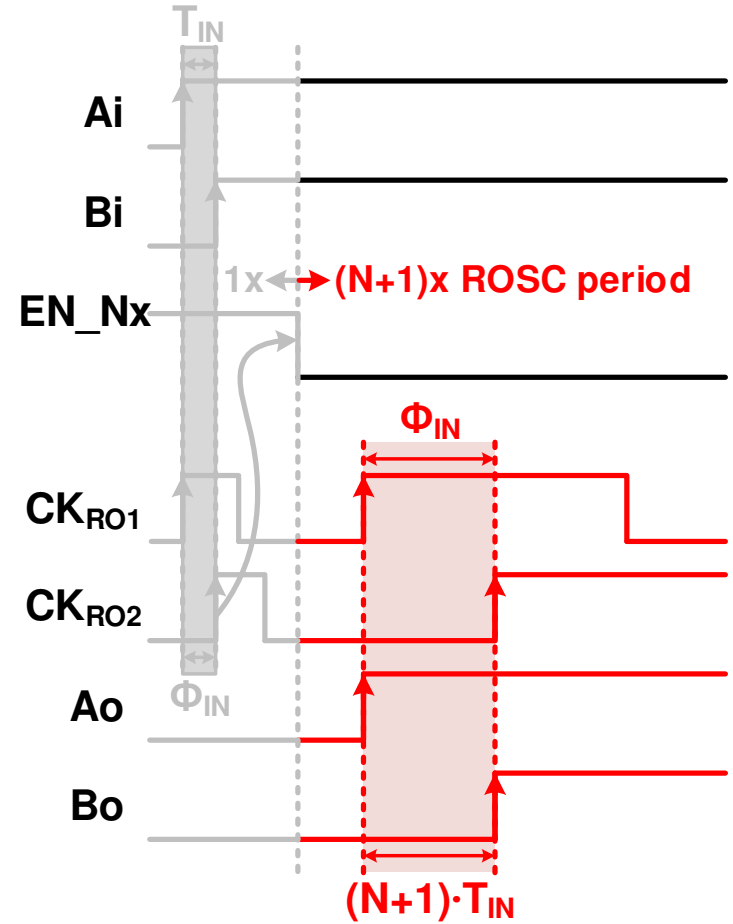
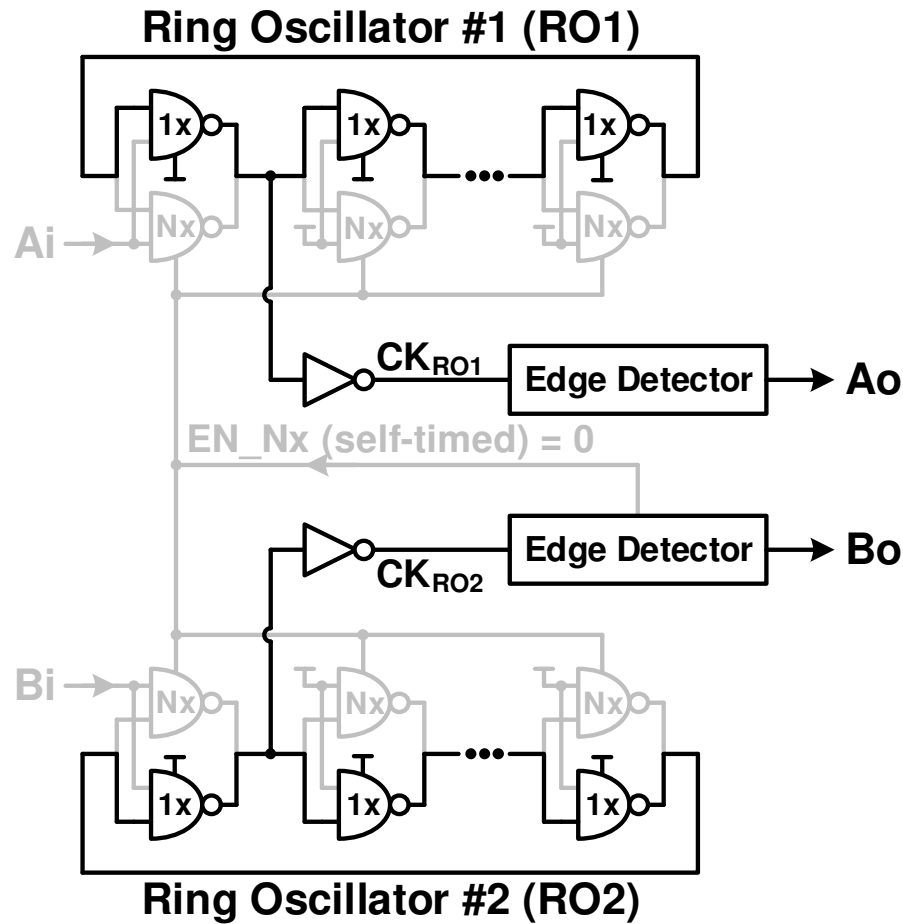
- ✓ Susceptible to variation due to summation of multiple pulses
- ✓ Requires a "gated" delay line based fine TDC

# Proposed Switched Ring-Osc TA



- Both 1x and Nx gates are switched on w/ input signals
- Initial frequency is  $(N+1)x$  with '1:N' NAND gate sizing

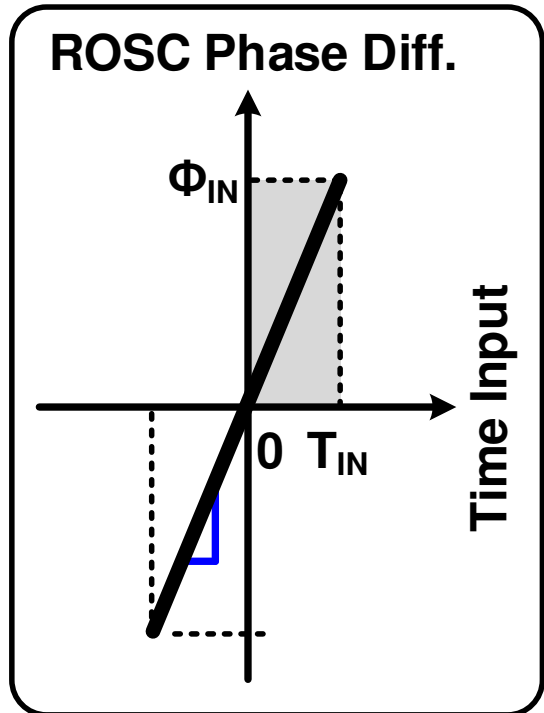
# Proposed Switched Ring-Osc TA



- $N_x$  gates are switched off by self-timed  $EN_{Nx}$  ( $1 \Rightarrow 0$ )
- ROOSC freq. reduces to  $1x \Rightarrow$  Time is amplified by  $(N+1)x$

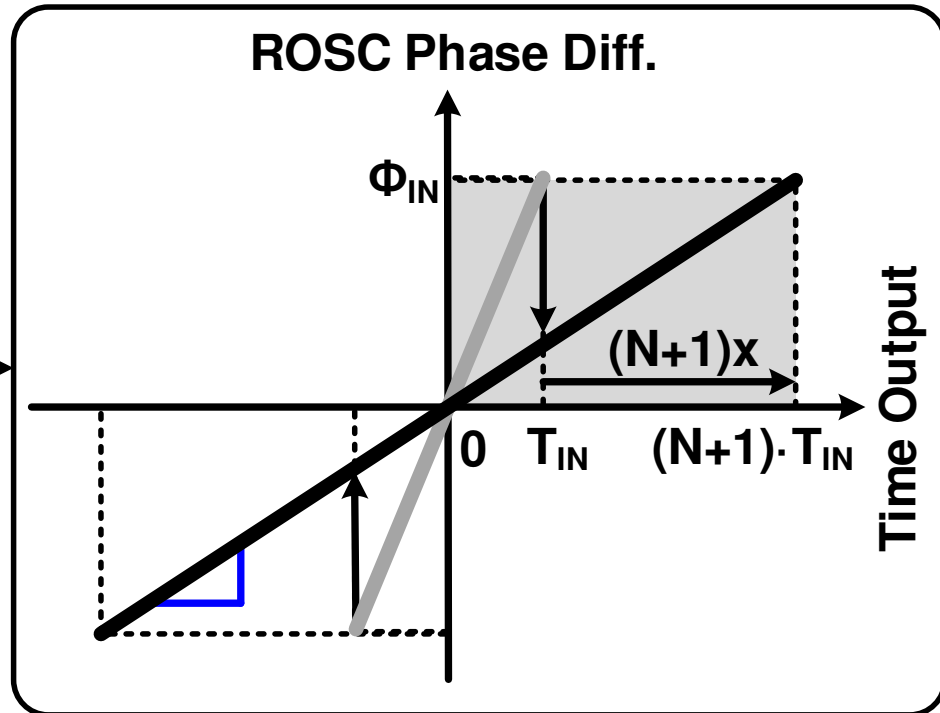
# Mechanism of Proposed SRO-TA

[Before Switching]



$$\Phi_{IN} = \underbrace{2\pi \cdot f_{ROSC}}_{\text{(slope)}} \cdot T_{IN}$$

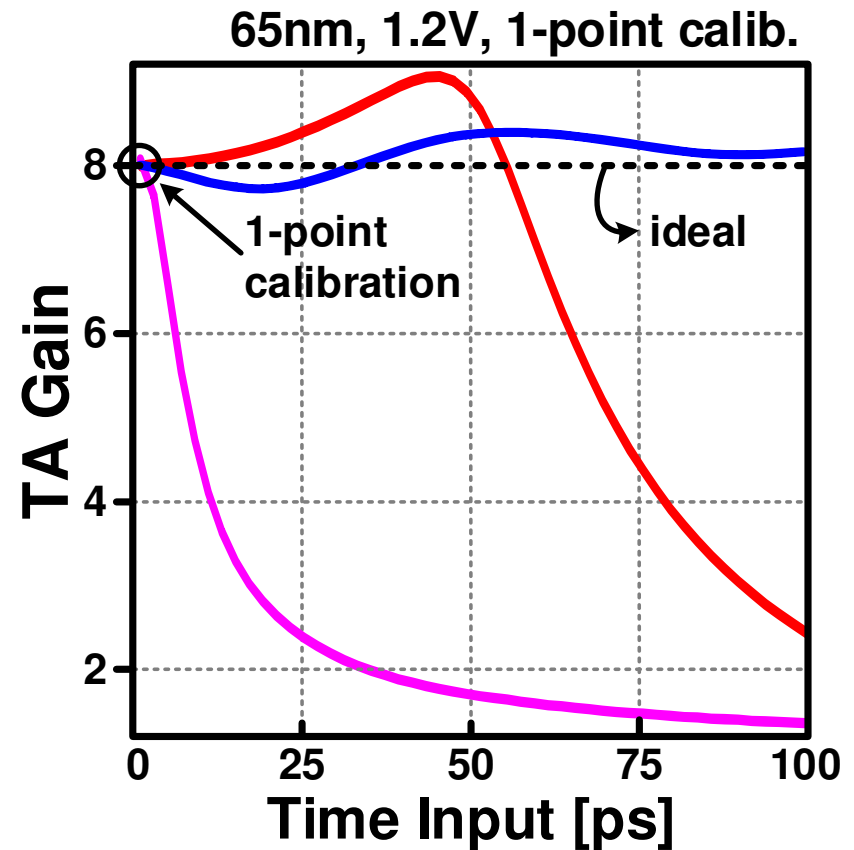
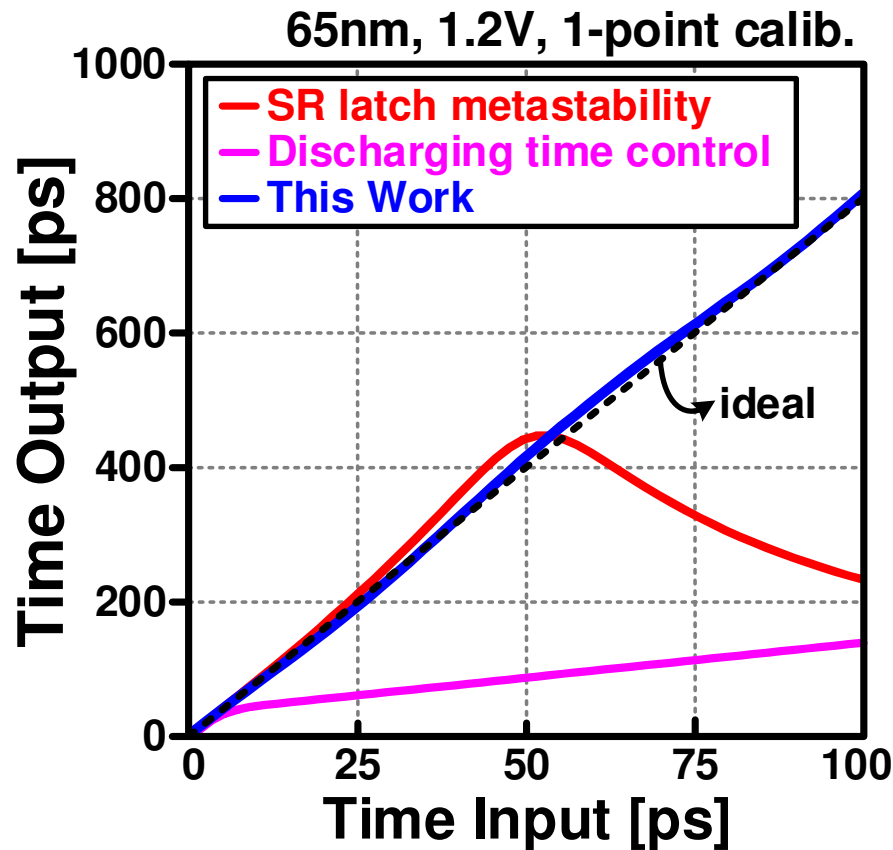
[After Switching]



$$\Phi_{IN} = \underbrace{2\pi \cdot (f_{ROSC}/(N+1))}_{\text{(slope)}} \cdot (N+1)T_{IN}$$

- The slope in the graph represents ring oscillator frequency

# Time Amplifier Simulation Results



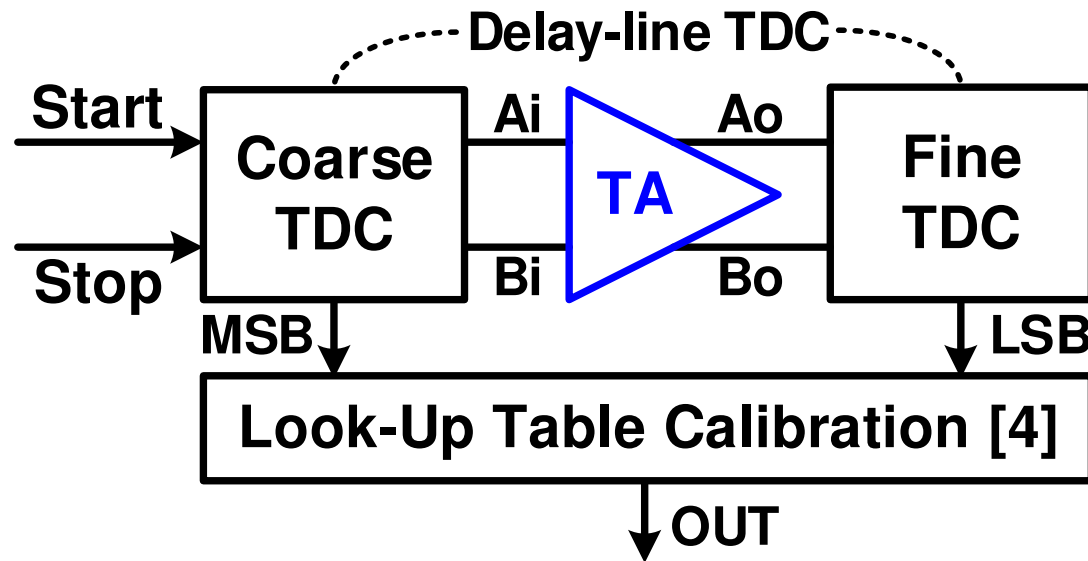
- Existing TA gain error: -71% to 15% and -83% to 3%
- Proposed TA gain error: -4% to 5% @ 100ps input range

# Comparison with Existing TAs

	TA Principle	Analog/Digital (Gain Control)	Predictable TA Gain	Required Fine TDC
[1] VLSI'07*	Metastability	Analog	NO	Delay-line
[2] ISSCC'10*	Discharging Time Ctrl	Analog	YES (with calib.)	Delay-line
[3] VLSI'12*	Pulse Train	Digital	YES	Gated Delay-line
This Work	Switched ROSC	Digital	YES	Delay-line

\*Original publications where the TA circuits were firstly introduced

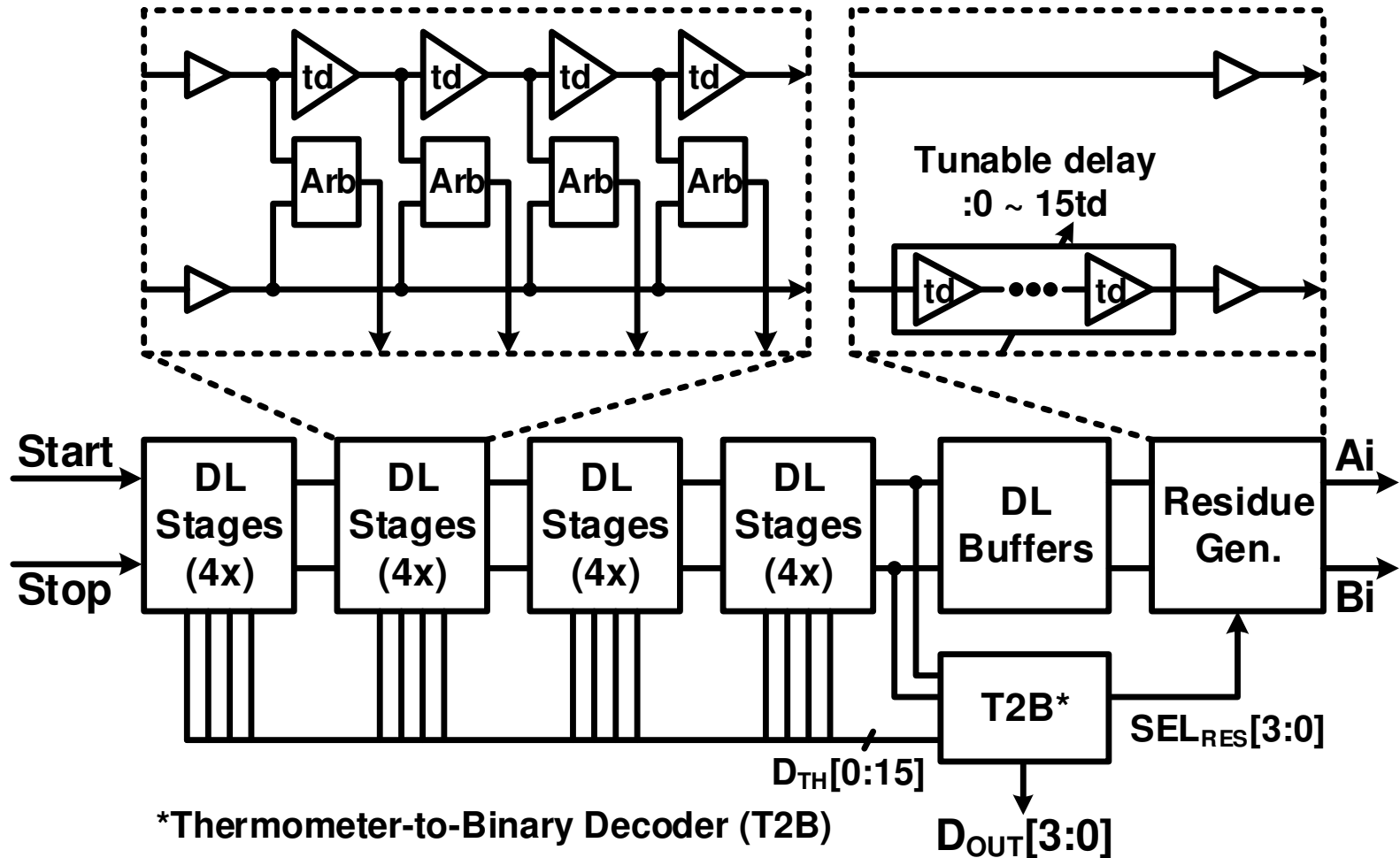
# Implemented Two-Step TDC



	6b	7b	8b
Coarse	4b		
TA	4x	8x	16x
Fine	2b	3b	4b

- Proposed two-step TDC consists of coarse/fine delay line TDCs and a proposed time amplifier in between them
- A LUT-based calibration is used to improve TDC linearity

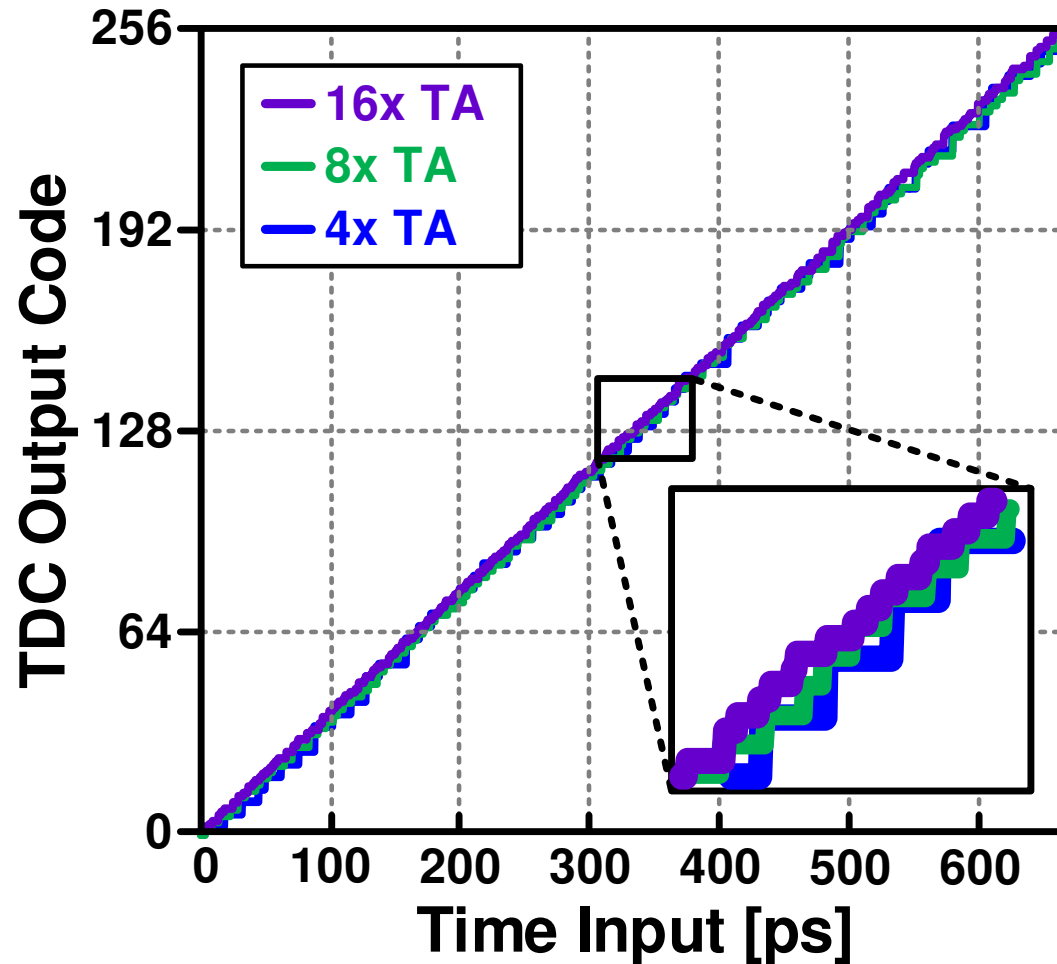
# 4bit Delay Line TDC Circuit



- A 4b delay line TDC is used for both coarse and fine TDCs

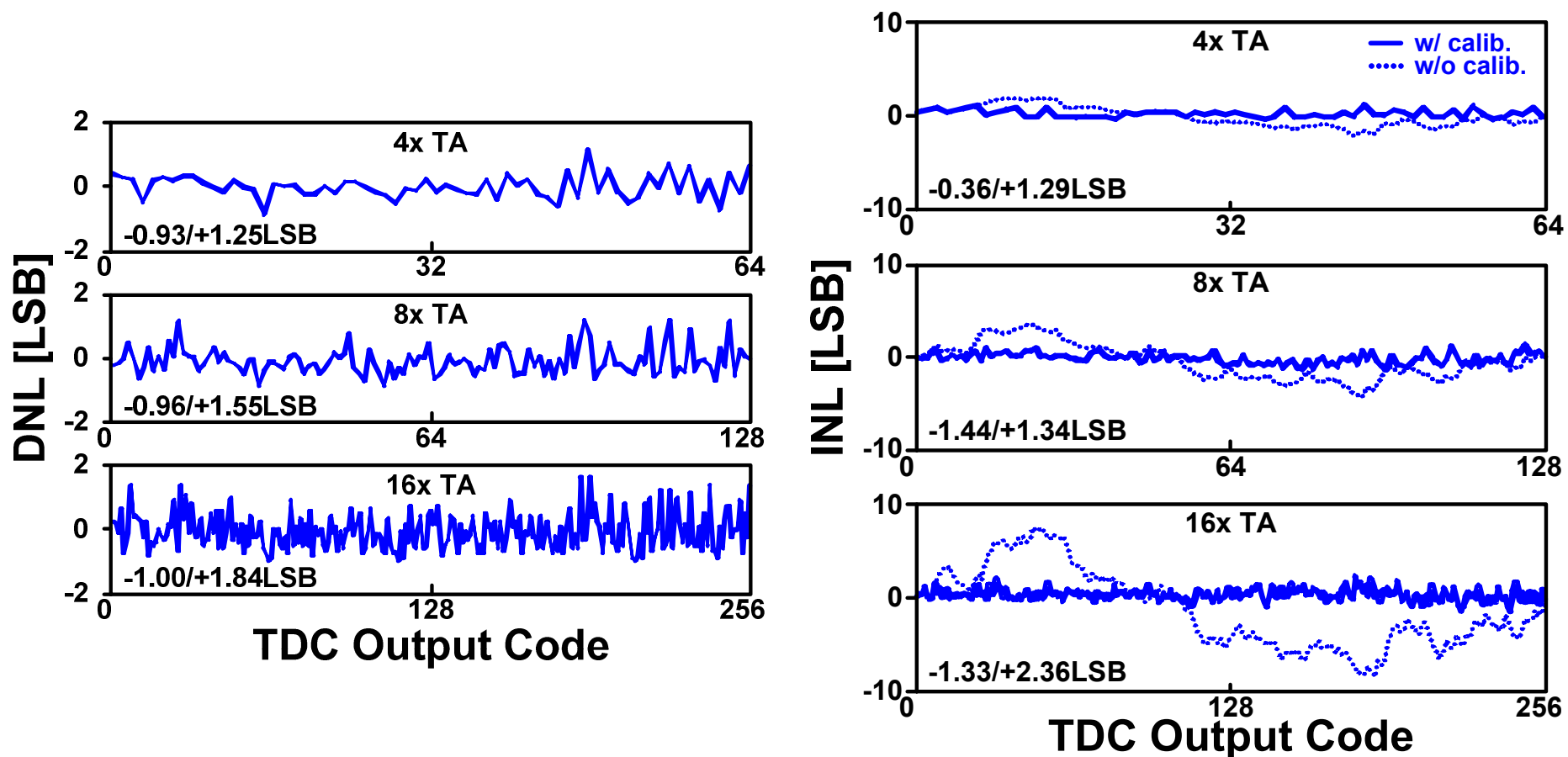


# Measured Output vs. Ramp Input



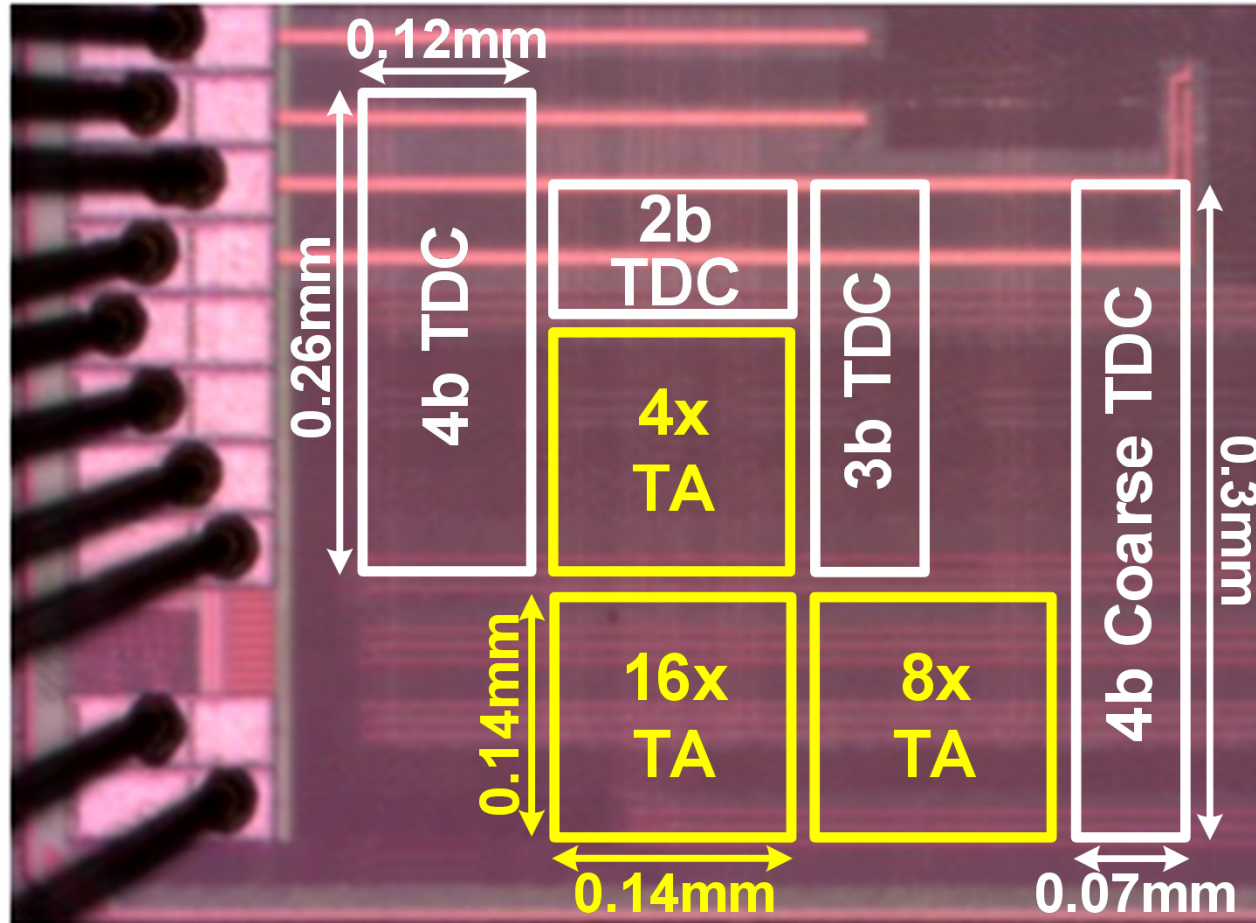
- Measured TDC outputs with respect to a ramp time input

# Measured DNL and INL



- Implemented 6/7/8bit two-step TDC with 4/8/16x TA
- Achieved maximum DNL of 1.84LSB and INL of 2.36LSB

# 65nm Test-Chip Micrograph



# Performance Comparison

	[6] CICC'09	[2] VLSI'11	[3] VLSI'12	This Work
<b>Process</b>	65nm	130nm	65nm	65nm
<b>Scheme</b>	Vernier	Pipeline	Two-Step	Two-Step
<b>Resolution</b>	4.80ps	0.63ps	3.75ps	2.60ps
<b>Bits</b>	7	11	7	8
<b>Conv. Rate</b>	50MS/s	65MS/s	200MS/s	80MS/s
<b>Max. DNL</b>	1LSB	0.5LSB	0.9LSB	1.84LSB
<b>Max. INL</b>	3.3LSB	9LSB	2.3LSB	2.36LSB
<b>Power</b>	1.7mW	10.5mW	3.6mW	2mW
<b>Area</b>	0.07mm <sup>2</sup>	0.32mm <sup>2</sup>	0.02mm <sup>2</sup>	0.07mm <sup>2</sup>

# Conclusion

- **A switched ring oscillator based time amplifier is proposed and fabricated in 65nm CMOS**
- **An 8bit two-step TDC based on the proposed TA achieves 2.6ps time resolution with 16x TA**
- **Measured TDC DNL and INL results show 1.84 and 2.36 LSB while consuming 2mW at 80MS/s and occupying 0.07mm<sup>2</sup>**